Substitute Form PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office Attorney's Docket No. 05770-138001

Application No. 09/658,838

7 2 2003

mati n Disclosur Statement by Applicant (Use several sheets if necessary) Applicant

David M. Buczek et al.

Filing Date September 8, 2000 Group Art Unit 2827

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